



European Conference on X-Ray Spectrometry

EXRS2016

Gothenburg, Sweden
19 - 24 June 2016

<http://exrs2016.se>



Conference topics

- Interactions of X-rays with matter and fundamental parameters
- XRS Instrumentation (X-ray sources, optics and detectors)
- Quantification methodology and metrology
- TXRF, GIXRF and related techniques
- Microbeam techniques, confocal XRF and X-Ray imaging
- Mobile and portable XRF
- Synchrotron XRS, XAFS, high resolution XES, and RIXS
- PIXE instrumentation and applications
- Electron induced XRS
- WDXRS
- X-ray diffraction (XRD)
- XRS in Art and Cultural Heritage
- XRS in Advanced Materials and Nanoscience
- XRS in Earth and Environment sciences
- XRS in Industrial Quality and Process Control
- XRS in Life Sciences and Forensics
- Recent Scientific Developments by XRS Instrumentation

Organized by:

University of Gothenburg,
Gothenburg, Sweden

Chair: Johan Boman, chair@exrs2016.se

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Invited speakers

- Thomas CALLIGARO - Centre de Recherche et de
Restauration des Musées de France, Paris, France
Gerald FALKENBERG - DESY, Hamburg, Germany
Ursula FITTSCHEN - Washington State University, Pullman, USA
Shinsuki KUNIMURA - Tokyo University of Science, Japan
Juan Jose LEANI - Universidad Nacional de Córdoba,
Córdoba, Argentina
Liqiang LUO - National Research Center of Geoanalysis,
Beijing, China
Victor MALKA - LOA ENSTA /
Ecole Polytechnique, Chemin de la Hunière,
Palaiseau cedex, France
Serguei MOLODTSOV - European XFEL,
Hamburg, Germany
Richard NEUTZE - University of Gothenburg,
Gothenburg, Sweden
Silvia PANI - University of Surrey, Guildford, UK
Francesco Paolo ROMANO - IBAM-CNR, Catania, Italy
Jose Paolo SANTOS - Universidade NOVA de Lisboa,
Lisbon, Portugal
Menoj TIWAR - Indus Synchrotrons Utilization Division,
Raja Ramanna Centre for Advanced Technology,
Indore, Madhya Pradesh, India
Joel ULLOM - NIST, USA
Piet VAN ESPEN - Universiteit Antwerpen,
Antwerp, Belgium

